

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of: **Spencer M. Gold, et al.**

Serial No.: **Not Yet Assigned**

Filed: **Herewith**

For: **A CONTROLLER FOR MONITORING  
TEMPERATURE**

Attorney Docket No.: **SMQ-089/P6550**

Group Art Unit:

Examiner:

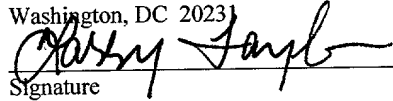
**BOX PATENT APPLICATION**

Commissioner for Patents  
Washington, D.C. 20231

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Date of Deposit February 19, 2002

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Signature

Larry Taylor

Please Print Name of Person Signing

**PRELIMINARY AMENDMENT**

Dear Sir:

Preliminary to examination of the above-referenced patent application, please  
amend the application as follows:

**In the Specification:**

Please replace the paragraph of page 1, lines 4-7 with the following:

2002 FEB 19 5 24 PM

The present invention relates to five other applications filed on the same date: A Method and System for Monitoring and Profiling an Integrated Circuit Die Temperature (Atty. Docket: SMQ-087/P6548), An Integrated Temperature Sensor (Atty. Docket: SMQ-088/P6549), Quantifying a Difference Between Nodal Voltages (Atty. Docket: 03226.116001/P6348), Low Voltage Temperature Independent and Temperature Dependent Voltage Generator (Atty. Docket: 03226.112001/P6322) and Temperature Calibration Using On-Chip Electrical Fuses (Atty. Docket: 03226.108001/P6216).

**REMARKS**

The above amendment introduces no new subject matter. Entry of the foregoing Preliminary Amendment is in order and requested. If there are any questions regarding the proposed amendment to the application, we invite the Examiner to call Applicants' attorney at the telephone number below.

Respectfully submitted,

LAHIVE & COCKFIELD, LLP



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Date: February 19, 2002

**“VERSION WITH MARKINGS TO SHOW CHANGES MADE”**

**In the Specification:**

Please amend the paragraph of page 1 lines 4-7 with the following:

The present invention relates to five [two] other applications filed on the same date: A Method and System for Monitoring and Profiling an Integrated Circuit Die Temperature (Atty. Docket: SMQ-087/P6548[/MDF]), An Integrated Temperature Sensor (Atty. Docket: SMQ-088/P6549[/MDF]), Quantifying a Difference Between Nodal Voltages (Atty. Docket: 03226.116001/P6348), Low Voltage Temperature Independent and Temperature Dependent Voltage Generator (Atty. Docket: 03226.112001/P6322) and Temperature Calibration Using On-Chip Electrical Fuses (Atty. Docket: 03226.108001/P6216).